



Contribution ID: **210**

Type: **Oral**

MUG Agenda

Wednesday, 13 September 2017 14:50 (1h 15m)

- General news from the CERN Foundry Service Team (10min)
- Single Event Latchup in 130nm circuits (10min)
- Stability of the TID response of 130 and 65nm technologies (5min)
- Total Ionising Dose response of 65nm MOSFETs irradiated to ultra-high doses (40min)
- Plans for the simulation of irradiated transistors in 65nm CMOS (5min)
- Plans for the evaluation of the TID effects in 40 and 28nm CMOS (5min)

Summary

Presenter: FACCIO, Federico (CERN)

Session Classification: Working Group